

Search Notes

Application/Control No.

10/580,451

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

KOHEN, RAN

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	21	4/07	hmh
439	20		
439	13		
439	537		
439	953		
439	23		
439	348		
439	320		
439	321	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner